

<b>Notice of References Cited</b>	Application/Control No. 10/560,723		Applicant(s)/Patent Under Reexamination EINSTEIN ET AL.	
	Examiner SEAN E. AEDER		Art Unit 1642	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,812,339 B1	11-2004	Venter et al.	536/24.31
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*	N	WO 01/60860 A2	08-2001		Schlegel et al	
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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